

温度测试表

版本：R&D-PTR-V1.2

Product Name		LLS-WZB-W40-L6-RDM									
High-temperature test											
ambient temperature		30 degrees Celsius			Test environment		Non-ventilated environment				
Drive current		0.5 ampere				power	15W		Working voltage		100V, 220V, 277V
Selection of test items		☒ LED beads ☒ Low-voltage drive and control ☒ Light panel ☒ Lamp body ☐ Switching power supply (high-voltage constant current drive)									
temperature Test Data	Component		Probe No.	100V		220V		277V			
	Master control IC: UCS512C4		CH01	52.6 degrees Celsius		52.3 degrees Celsius		52.4 degrees Celsius			
	Driver IC: U1		CH02	67.1 degrees Celsius		66.9 degrees Celsius		67.0 degrees Celsius			
	Driver IC: U2		CH03	64.0 degrees Celsius		63.7 degrees Celsius		63.9 degrees Celsius			
	Driver IC: U3		CH04	65.8 degrees Celsius		65.6 degrees Celsius		65.7 degrees Celsius			
	Driver IC: U4		CH05	63.3 degrees Celsius		63.1 degrees Celsius		63.0 degrees Celsius			
	The temperature inside the lamp tube cavity		CH06	44.6 degrees Celsius		44.4 degrees Celsius		44.3 degrees Celsius			
	Negative pole of L11 lamp bead		CH07	49.2 degrees Celsius		48.4 degrees Celsius		49.1 degrees Celsius			
	Negative pole of lamp bead L2		CH08	46.5 degrees Celsius		46.3 degrees Celsius		46.4 degrees Celsius			
	Lamp body		CH09	42.9 degrees Celsius		42.5 degrees Celsius		42.7 degrees Celsius			
Test conclusion											
Test items				Judgment criteria				Determine whether it is qualified.		Rectification Plan	
Determination of the temperature of red LED chips				The temperature at the lamp base + thermal resistance × power < 85℃							
Determination of the temperature of green LED chips				The temperature at the lamp base + thermal resistance × power < 85℃							
Determination of the temperature of blue LED chips				The temperature at the lamp base + thermal resistance × power < 85℃							
Determination of the temperature of white LED chips				The temperature at the lamp base + thermal resistance × power < 85℃							
Temperature determination of the driver chip				Below 100℃							
Capacitance temperature determination				Below 105℃							
Inductor temperature determination				Below 100℃							
Temperature determination of the flyback diode				Below 100℃							
Control chip determination				85℃							
Determination of lamp body temperature				Below 70℃							
Transformer temperature determination				Below 100℃							
MOSFET Temperature Determination				Below 100℃							
Output diode temperature determination				Below 100℃							

Test date: July 12, 2023

Signature of Project Engineer:

Tester's signature: Li Lei